

| L Number | Hits    | Search Text   | DB  | Time stamp       |
|----------|---------|---|---|------------------|
| -        | 2547    | 250/310   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/03/16 09:47 |
| -        | 3406    | 250/311   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/03/16 09:47 |
| -        | 4711    | 250/492.2   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/03/16 09:48 |
| -        | 2270    | 250/307   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/03/16 09:48 |
| -        | 312     | 250/440.11  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/03/16 09:48 |
| -        | 0       | (Transmission near2 electron near2 (microscope or microscopy) or TEM) and<br>(Beam or probe or arm or (micro near2 hand) or tip or needle))   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/03/16 09:58 |
| -        | 1079868 | @pd>20030801  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/03/16 11:11 |
| -        | 10531   | 250/310 or 250/311 or 250/492.2 or 250/307 or 250/440.11  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/03/16 11:07 |
| -        | 76215   | (Beam or probe or arm or (micro near2 hand) or tip or needle) and<br>(((scanning adj electron adj microscope) or<br>(scanning near3 microscope) or SEM) or (ion adj beam))            | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/03/16 11:07 |
| -        | 8551    | ((Transmission near2 electron near2 (microscope or microscopy or TEM)) and<br>(Beam or probe or arm or (micro near2 hand) or tip or needle))  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/03/16 11:10 |
| -        | 6740    | ((Transmission near2 electron near2 (microscope or microscopy or TEM)) and<br>(Beam or probe or arm or (micro near2 hand) or tip or needle)) and<br>(sample or workpiece or specimen) | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/03/16 11:31 |
| -        | 2395797 | @pd>20021219  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/03/16 11:11 |

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|---|---------|--|---|------------------|
| - | 334349  | @ad>20021219   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/03/16 11:11 |
| - | 14670   | @ad>20030801   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/03/16 11:11 |
| - | 2395911 | @pd>20021219 or @ad>20021219   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/03/16 11:11 |
| - | 1079969 | @pd>20030801 or @ad>20030801   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/03/16 11:11 |
| - | 605     | ((@pd>20030801 or @ad>20030801) and (250/310 or 250/311 or 250/492.2 or 250/307 or 250/440.11))  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/03/16 11:12 |
| - | 337     | ((@pd>20030801 or @ad>20030801) and (250/310 or 250/311 or 250/492.2 or 250/307 or 250/440.11)) and ((Beam or probe or arm or (micro near2 hand) or tip or needle) and (((scanning adj electron adj microscope) or (scanning near3 microscope) or SEM) or (ion adj beam)))   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/03/16 11:12 |
| - | 54      | ((@pd>20030801 or @ad>20030801) and (250/310 or 250/311 or 250/492.2 or 250/307 or 250/440.11)) and (((Transmission near2 electron near2 (microscope or microscopy or TEM)) and (Beam or probe or arm or (micro near2 hand) or tip or needle)) and (sample or workpiece or specimen))  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/03/16 11:12 |
| - | 107     | ((@pd>20021219 or @ad>20021219) and (250/310 or 250/311 or 250/492.2 or 250/307 or 250/440.11) and (((Transmission near2 electron near2 (microscope or microscopy or TEM)) and (Beam or probe or arm or (micro near2 hand) or tip or needle)) and (sample or workpiece or specimen))   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/03/16 11:13 |
| - | 888660  | (Beam or probe or arm or (micro near2 hand) or tip or needle) SAME (rotat\$5 or circ\$5)   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/03/16 11:22 |
| - | 60      | ((Beam or probe or arm or (micro near2 hand) or tip or needle) SAME (rotat\$5 or circ\$5)) and ((@pd>20021219 or @ad>20021219) and (250/310 or 250/311 or 250/492.2 or 250/307 or 250/440.11) and (((Transmission near2 electron near2 (microscope or microscopy or TEM)) and (Beam or probe or arm or (micro near2 hand) or tip or needle)) and (sample or workpiece or specimen))) | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/03/16 11:18 |
| - | 625608  | (Beam or probe or arm or (micro near2 hand) or tip or needle) WITH (rotat\$5 or circ\$5)   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/03/16 11:21 |

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| - | 587309 | (Beam or probe or arm or (micro near2 hand) or tip or needle) WITH (rotat\$5 or Circle or circular or pivot)  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/03/16 11:22 |
| - | 23124  | (((Transmission near2 electron near2 (microscope or microscopy or TEM)) or SEM or (scanning adj electron adj microscope)) and (Beam or probe or arm or (micro near2 hand) or tip or needle)) and (sample or workpiece or specimen)  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/03/16 11:31 |
| - | 342    | ((@pd>20021219 or @ad>20021219) and (250/310 or 250/311 or 250/492.2 or 250/307 or 250/440.11) and (((Transmission near2 electron near2 (microscope or microscopy or TEM)) or SEM or (scanning adj electron adj microscope)) and (Beam or probe or arm or (micro near2 hand) or tip or needle)) and (sample or workpiece or specimen)   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/03/16 11:31 |
| - | 30     | )<br>((Beam or probe or arm or (micro near2 hand) or tip or needle) WITH (rotat\$5 or Circle or circular or pivot)) and (((@pd>20021219 or @ad>20021219) and (250/310 or 250/311 or 250/492.2 or 250/307 or 250/440.11) and (((Transmission near2 electron near2 (microscope or microscopy or TEM)) and (Beam or probe or arm or (micro near2 hand) or tip or needle)) and (sample or workpiece or specimen))   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/03/16 12:03 |
| - | 95     | (((@pd>20021219 or @ad>20021219) and (250/310 or 250/311 or 250/492.2 or 250/307 or 250/440.11) and (((Transmission near2 electron near2 (microscope or microscopy or TEM)) or SEM or (scanning adj electron adj microscope)) and (Beam or probe or arm or (micro near2 hand) or tip or needle)) and (sample or workpiece or specimen))<br><br>) and ((Beam or probe or arm or (micro near2 hand) or tip or needle) WITH (rotat\$5 or Circle or circular or pivot)) | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/03/16 12:03 |